WEST Search History

Hitle liams | Restore | Clear | Cancel |

DATE: Tuesday, December 07, 2004

Hide? Set Name Query			Hit Count	
DB=USPT; PLUR=NO; OP=ADJ				
	L44	11 and 139	2	
	L43	l1 and l40	16	
	L42	L40 and 139	0	
	L41	L40 and l39 and (l4 or l1)	0	
	L40	(holding or waiting) adj1 (routine or process or method or algorithm)	1532	
	L39	instance adj1 monitor\$4	533	
	L38	132 and 14	8	
	L37	L36 and (lock\$1 and l9) and (l21 or l10)	23	
	L36	11 and (12 or 13)	58	
	L35	19 and 110 and 111	0	
-	L34	L33 and 11	1	
	L33	L32 and (l2 or l21)	16	
	L32	parent same child same lock\$1	138	
	L31	110 same 14	1	
	L30	121 and 11	3	
	L29	,17 and 11	0	
	L28	17 and 14	0	
	L27	17 and 18 and (11 or 14)	0	
	L26	14 same 13	0	
	L25	L24 and (l2 or l4)	9	
	L24	L23 and 13	39	
	L23	707/\$.ccls.	14009	
	L22	L21 and 119	2	
	L21	holding adj1 (child or process)	730	
	L20	L19 and terminati\$6	4	
	L19	117 and (15 or 16 or 17 or 18 or 19 or 111 or 112)	22	
	L18	L17 and (fork\$3)	0	
	L17	L16 and 14	23	
	L16	11 and (12 or 13)	58	
	L15	12 and 13 and 14	0	
	L14	11 and 12 and 13 and 14	0	
			:	

L13	17 same 18	0
L12	validation adj1 (module or unit or repository)	257
L11	non-standard adj1 error\$1	2
L10	waiting near3 process	2699
L9	application	1942937
L8	application adj1 instance	987
L7	detecting adj1 termination	423
L6	ready adj1 signal	5745
L5	signal	969829
L4	exclusive adj1 lock\$1	345
L3	fork\$3 near3 (child or process or parent)	556
L2	(waiting or holding) near3 (process or child)	7453
L1	(707/8).ccls.	727

END OF SEARCH HISTORY

Print Format

IEEE HOME I SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publica	ations/Services Standards Conferences Careers/Jobs	
IEEE)	Welcome United States Patent and Trademark Office	
Help FAQ Terms IEE	Quick Links	» Se
Welcome to IEEE Xplores - Home - What Can I Access?	Your search matched 0 of 1099723 documents. A maximum of 500 results are displayed, 15 to a page, sorted by Rel Descending order.	evance
O- Log-out	Refine This Search:	
Tables of Contents	You may refine your search by editing the current search expression of new one in the text box.	r enteri
O- Journals & Magazines	holding and child and lock Search	
Conference Proceedings	☐ Check to search within this result set	:
O- Standards	Results Key: JNL = Journal or Magazine CNF = Conference STD = Standard	
Search		
O- By Author O- Basic O- Advanced O- CrossRef	Results: No documents matched your query.	
Member Services		
O- Join IEEE O- Establish IEEE Web Account O- Access the IEEE Member Digital Library		
O- Access the IEEE Enterprise File Cabinet		

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account |
New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online
Publications | Help | FAQ| Terms | Back to Top

Copyright © 2004 IEEE — All rights reserved

ch

h eee e eee g e ch e ch e e e h g

IEEE HOME I SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE

Publications/Services Standards Conferences Careers/Jobs



Welcome **United States Patent and Trademark Office** » Se. **Quick Links** FAQ Terms IEEE Peer Review Welcome to IEEE Xplores Your search matched 0 of 1099723 documents. O- Home A maximum of 500 results are displayed, 15 to a page, sorted by Relevance — What Can Descending order. I Access? O- Log-out **Refine This Search:** You may refine your search by editing the current search expression or entering **Tables of Contents** new one in the text box. Journals Search (parent or child) and exclusive and lock & Magazines ☐ Check to search within this result set C Conference **Proceedings Results Key:** Standards JNL = Journal or Magazine CNF = Conference STD = Standard Search O- By Author ()- Basic **Results:** No documents matched your query. O- Advanced ()- CrossRef Member Services O- Join IEEE O- Establish IEEE Web Account Access the **IEEE Member Digital Library** IEEE Enterprise — Access the **IEEE Enterprise File Cabinet** Print Format

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account |
New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online
Publications | Help | FAQ | Terms | Back to Top

Copyright © 2004 IEEE — All rights reserved

ch

h eee e eee g e ch e ch e e

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE

Membership Publications/Services Standards Conferences Careers/Jobs



IEEE)	Welcome United States Patent and Trademark Office	3
Help FAQ Terms IEE	Peer Review Quick Links	» Se
Welcome to IEEE Xplore*		
O- Home O- What Can I Access?	Your search matched 0 of 1099723 documents. A maximum of 500 results are displayed, 15 to a page, sorted by ReDescending order.	levance
O- Log-out	Refine This Search:	:
Tables of Contents	You may refine your search by editing the current search expression new one in the text box.	or enteri
O- Journals & Magazines	fork and lock and database Search	
O- Conference Proceedings	☐ Check to search within this result set	:
O- Standards	Results Key: JNL = Journal or Magazine CNF = Conference STD = Standard	:
Search - By Author - Basic - Advanced - CrossRef	Results: No documents matched your query.	
Member Services		1
O- Join IEEE O- Establish IEEE Web Account O- Access the IEEE Member Digital Library		
IEEE Enterprise	· ·	į
O- Access the IEEE Enterprise File Cabinet		
Print Format		

Home | Log-out | Journals | Conference Proceedings | Standards | Search by Author | Basic Search | Advanced Search | Join IEEE | Web Account |
New this week | OPAC Linking Information | Your Feedback | Technical Support | Email Alerting | No Robots Please | Release Notes | IEEE Online
Publications | Help | FAQ| Terms | Back to Top

Copyright © 2004 IEEE — All rights reserved